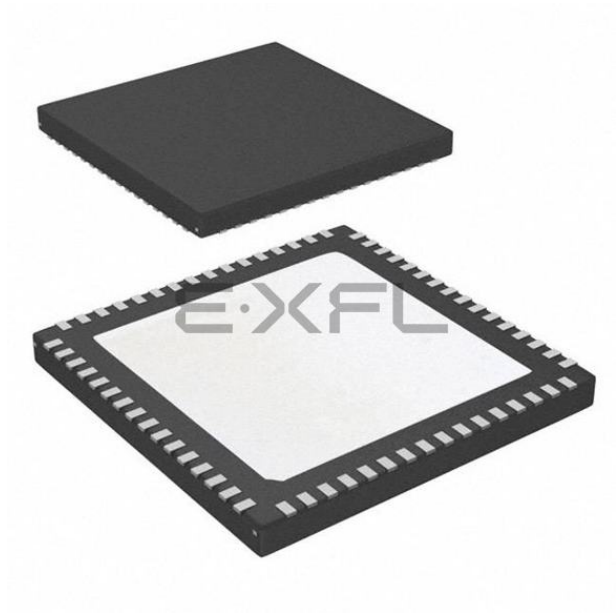

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Details	
Product Status	Not For New Designs
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	80MHz
Connectivity	EBI/EMI, I²C, IrDA, SmartCard, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, DMA, I²S, POR, PWM, WDT
Number of I/O	50
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 28x12b; D/A 2x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-VFQFN Exposed Pad
Supplier Device Package	64-QFN (9x9)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/sim3c166-b-gm

2. Typical Connection Diagrams

This section provides typical connection diagrams for SiM3C1xx devices.

2.1. Power

Figure 2.1 shows a typical connection diagram for the power pins of the SiM3C1xx devices when the internal regulator is in use.

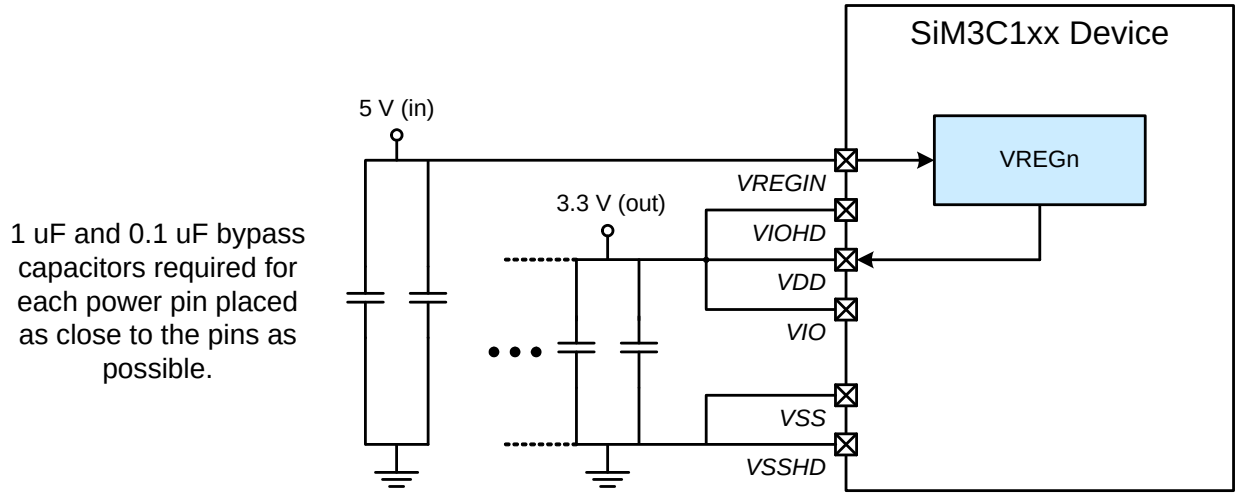


Figure 2.1. Connection Diagram with Voltage Regulator Used

Figure 2.2 shows a typical connection diagram for the power pins of the SiM3C1xx devices when the internal regulator is not used.

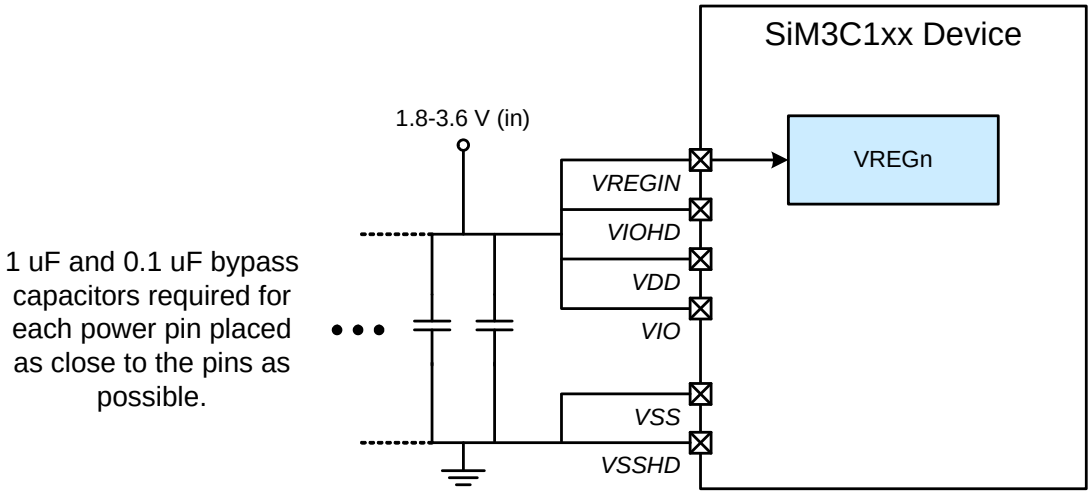


Figure 2.2. Connection Diagram with Voltage Regulator Not Used

3. Electrical Specifications

3.1. Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 3.1, unless stated otherwise.

Table 3.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD	V_{DD}		1.8	—	3.6	V
Operating Supply Voltage on VREGIN	V_{REGIN}	EXTVREG0 Not Used	4	—	5.5	V
		EXTVREG0 Used	3.0	—	3.6	V
Operating Supply Voltage on VIO	V_{IO}		1.8	—	V_{DD}	V
Operating Supply Voltage on VIOHD	V_{IOHD}	HV Mode (default)	2.7	—	6.0	V
		LV Mode	1.8	—	3.6	V
Voltage on I/O pins, Port Bank 0, 1 and 2 I/O	V_{IN}		V_{SS}	—	V_{IO}	V
Voltage on I/O pins, Port Bank 3 I/O and $\overline{\text{RESET}}$	V_{IN}	SiM3C1x7 PB3.0–PB3.7 and $\overline{\text{RESET}}$	V_{SS}	—	V_{IO}+2.0	V
		SiM3C1x7 PB3.8 - PB3.11	V_{SS}	—	Lowest of V_{IO}+2.0 or V_{REGIN}	V
		SiM3C1x6 PB3.0–PB3.5 and $\overline{\text{RESET}}$	V_{SS}	—	V_{IO}+2.0	V
		SiM3C1x6 PB3.6–PB3.9	V_{SS}	—	Lowest of V_{IO}+2.0 or V_{REGIN}	V
		SiM3C1x4 $\overline{\text{RESET}}$	V_{SS}	—	V_{IO}+2.0	V
		SiM3C1x4 PB3.0–PB3.3	V_{SS}	—	Lowest of V_{IO}+2.0 or V_{REGIN}	V
Voltage on I/O pins, Port Bank 4 I/O	V_{IN}		V_{SSHD}	—	V_{IOHD}	V
System Clock Frequency (AHB)	f_{AHB}		0	—	80	MHz
Peripheral Clock Frequency (APB)	f_{APB}		0	—	50	MHz
Operating Ambient Temperature	T_A		–40	—	85	°C
Operating Junction Temperature	T_J		–40	—	105	°C

Note: All voltages with respect to V_{SS}.

Table 3.2. Power Consumption

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Digital Core Supply Current						
Normal Mode[2,3,4,5]—Full speed with code executing from Flash, peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	33	36.5	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	10.5	13.3	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	2.0	3.8	mA
Normal Mode[2,3,4,5]—Full speed with code executing from Flash, peripheral clocks OFF	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	22	24.9	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	7.8	10	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.2	3	mA
Power Mode 1[2,3,4,6]—Full speed with code executing from RAM, peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	30.5	35.5	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	8.5	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.7	—	mA
Power Mode 1[2,3,4,6]—Full speed with code executing from RAM, peripheral clocks OFF	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	20	23	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	5.3	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.0	—	mA
Power Mode 2[2,3,4]—Core halted with peripheral clocks ON	I_{DD}	F_{AHB} = 80 MHz, F_{APB} = 40 MHz	—	19	22	mA
		$F_{AHB} = F_{APB}$ = 20 MHz	—	7.8	—	mA
		$F_{AHB} = F_{APB}$ = 2.5 MHz	—	1.3	—	mA
Power Mode 3[2,3]	I_{DD}	V_{DD} = 1.8 V, T_A = 25 °C	—	175	—	µA
		V_{DD} = 3.0 V, T_A = 25 °C	—	250	—	µA

Notes:
1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.2. Power Consumption (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Power Mode 9[2,3]—Low Power Shutdown with VREG0 disabled, powered through VDD and VIO	I_{DD}	RTC Disabled, V_{DD} = 1.8 V, T_A = 25 °C	—	85	—	nA
		RTC w/ 16.4 kHz LFO, V_{DD} = 1.8 V, T_A = 25 °C	—	350	—	nA
		RTC w/ 32.768 kHz Crystal, V_{DD} = 1.8 V, T_A = 25 °C	—	620	—	nA
		RTC Disabled, V_{DD} = 3.0 V, T_A = 25 °C	—	145	—	nA
		RTC w/ 16.4 kHz LFO, V_{DD} = 3.0 V, T_A = 25 °C	—	500	—	nA
		RTC w/ 32.768 kHz Crystal, V_{DD} = 3.0 V, T_A = 25 °C	—	800	—	nA
Power Mode 9[2,3]—Low Power Shutdown with VREG0 in low-power mode, VDD and VIO powered through VREG0 (Includes VREG0 current)	I_{VREGIN}	RTC Disabled, VREGIN = 5 V, T_A = 25 °C	—	300	—	nA
		RTC w/ 16.4 kHz LFO, VREGIN = 5 V, T_A = 25 °C	—	650	—	nA
		RTC w/ 32.768 kHz Crystal, VREGIN = 5 V, T_A = 25 °C	—	950	—	nA
VIOHD Current (High-drive I/O disabled)	I_{VIOHD}	HV Mode (default)	—	2.5	5	µA
		LV Mode	—	2	—	nA

Notes:

1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.2. Power Consumption (Continued)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Oscillator (EXTOSC0)[8]	I_{EXTOSC}	FREQCN = 111	—	3.8	4.7	mA
		FREQCN = 110	—	840	950	µA
		FREQCN = 101	—	185	220	µA
		FREQCN = 100	—	65	80	µA
		FREQCN = 011	—	25	30	µA
		FREQCN = 010	—	10	15	µA
		FREQCN = 001	—	5	10	µA
		FREQCN = 000	—	3	8	µA
SARADC0, SARADC1	I_{SARADC}	Sampling at 1 Msps, highest power mode settings.	—	1.2	1.5	mA
		Sampling at 250 ksps, lowest power mode settings.	—	390	510	µA
Temperature Sensor	I_{TSENSE}		—	75	105	µA
Internal SAR Reference	I_{REFFS}	Normal Power Mode	—	680	750	µA
		Low Power Mode	—	160	190	µA
VREF0	I_{REFP}		—	75	100	µA
Comparator 0 (CMP0), Comparator 1 (CMP1)	I_{CMP}	CMPMD = 11	—	0.5	—	µA
		CMPMD = 10	—	3	—	µA
		CMPMD = 01	—	10	—	µA
		CMPMD = 00	—	25	—	µA
Capacitive Sensing (CAPSENSE0)	I_{CS}	Continuous Conversions	—	55	80	µA
IDAC0[7], IDAC1[7]	I_{IDAC}		—	75	90	µA
IVC0[7]	I_{IVC}	I_{IN} = 0	—	1.5	2.5	µA
Voltage Supply Monitor (VMON0)	I_{VMON}		—	15	25	µA

Notes:

1. Perhipheral currents drop to zero when peripheral clock and peripheral are disabled, unless otherwise noted.
2. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
3. Includes all peripherals that cannot have clocks gated in the Clock Control module.
4. Includes supply current from internal regulator and PLL0OSC (>20 MHz) or LPOSC0 (<=20 MHz).
5. Flash execution numbers use 2 wait states for 80 MHz and 0 wait states at 20 MHz or less.
6. RAM execution numbers use 0 wait states for all frequencies.
7. IDAC output current and IVC input current not included.
8. Bias current only. Does not include dynamic current from oscillator running at speed.

Table 3.7. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Write Time[1]	t_{WRITE}	One 16-bit Half Word	20	21	22	µs
Erase Time[1]	t_{ERASE}	One Page	20	21	22	ms
	t_{ERALL}	Full Device	20	21	22	ms
V_{DD} Voltage During Programming	V_{PROG}		1.8	—	3.6	V
Endurance (Write/Erase Cycles)	N_{WE}		20k	100k	—	Cycles
Retention[2]	t_{RET}	T_A = 25 °C, 1k Cycles	10	100	—	Years

Notes:
1. Does not include sequencing time before and after the write/erase operation, which may take up to 35 µs. During a sequential write operation, this extra time is only taken prior to the first write and after the last write.
2. Additional Data Retention Information is published in the Quarterly Quality and Reliability Report.

Table 3.8. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Phase-Locked Loop (PLL0OSC)						
Calibrated Output Frequency*	$f_{PLL0OSC}$	Full Temperature and Supply Range	77	79	80	MHz
Power Supply Sensitivity*	$PSS_{PLL0OSC}$	T_A = 25 °C, Fout = 79 MHz	—	430	—	ppm/V
Temperature Sensitivity*	$TS_{PLL0OSC}$	V_{DD} = 3.3 V, Fout = 79 MHz	—	95	—	ppm/°C
Adjustable Output Frequency Range	$f_{PLL0OSC}$		23	—	80	MHz
Lock Time	$t_{PLL0LOCK}$	f_{REF} = 20 MHz, $f_{PLL0OSC}$ = 80 MHz, M=24, N=99, LOCKTH = 0	—	1.7	—	µs
		f_{REF} = 32 kHz, $f_{PLL0OSC}$ = 80 MHz, M=0, N=2440, LOCKTH = 0	—	91	—	µs

***Note:** PLL0OSC in free-running oscillator mode.

Table 3.17. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Standard I/O (PB0, PB1, and PB2), 5 V Tolerant I/O (PB3), and $\overline{\text{RESET}}$						
Output High Voltage*	V_{OH}	Low Drive, I_{OH} = –2 mA	V_{IO} – 0.7	—	—	V
		High Drive, I_{OH} = –5 mA	V_{IO} – 0.7	—	—	V
Output Low Voltage*	V_{OL}	Low Drive, I_{OL} = 3 mA	—	—	0.6	V
		High Drive, I_{OL} = 12.5 mA	—	—	0.6	V
Input High Voltage	V_{IH}	1.8 ≤ V_{IO} ≤ 2.0	0.7 x V_{IO}	—	—	V
		2.0 ≤ V_{IO} ≤ 3.6	V_{IO} – 0.6	—	—	V
Input Low Voltage	V_{IL}		—	—	0.6	V
Pin Capacitance	C_{IO}	PB0, PB1 and PB2 Pins	—	4	—	pF
		PB3 Pins	—	7	—	pF
Weak Pull-Up Current (Input Voltage = 0 V)	I_{PU}	V_{IO} = 1.8	–6	–3.5	–2	µA
		V_{IO} = 3.6	–30	–20	–10	µA
Input Leakage (Pullups off or Analog)	I_{LK}	0 ≤ V_{IN} ≤ V_{IO}	–1	—	1	µA
Input Leakage Current of Port Bank 3 I/O, V_{IN} above V_{IO}	I_L	V_{IO} < V_{IN} < V_{IO}+2.0 V (pins without EXREG functions)	0	5	150	µA
		V_{IO} < V_{IN} < V_{REGIN} (pins with EXREG functions)	0	5	150	µA
High Drive I/O (PB4)						
Output High Voltage	V_{OH}	Standard Mode, Low Drive, I_{OH} = –3 mA	V_{IOHD} – 0.7	—	—	V
		Standard Mode, High Drive, I_{OH} = –10 mA	V_{IOHD} – 0.7	—	—	V
Output Low Voltage	V_{OL}	Standard Mode, Low Drive, I_{OH} = 3 mA	—	—	0.6	V
		Standard Mode, High Drive, I_{OH} = 12.5 mA	—	—	0.6	V
Output Rise Time	t_R	Slew Rate Mode 0, V_{IOHD} = 5 V	—	50	—	ns
		Slew Rate Mode 1, V_{IOHD} = 5 V	—	300	—	ns
		Slew Rate Mode 2, V_{IOHD} = 5 V	—	1	—	µs
		Slew Rate Mode 3, V_{IOHD} = 5 V	—	3	—	µs

***Note:** $\overline{\text{RESET}}$ does not drive to logic high. Specifications for $\overline{\text{RESET}}$ V_{OL} adhere to the low drive setting.

volatile data storage and allowing field upgrades of the firmware. User firmware has complete control of all peripherals and may individually shut down and gate the clocks of any or all peripherals for power savings.

The on-chip debugging interface (SWJ-DP) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging.

Each device is specified for 1.8 to 3.6 V operation over the industrial temperature range (–40 to +85 °C). The Port I/O and RESET pins are powered from the IO supply voltage. The SiM3C1xx devices are available in 40-pin or 64-pin QFN, 64-pin or 80-pin TQFP, or 92-pin LGA packages. All package options are lead-free and RoHS compliant. See Table 5.1 for ordering information. A block diagram is included in Figure 4.1.

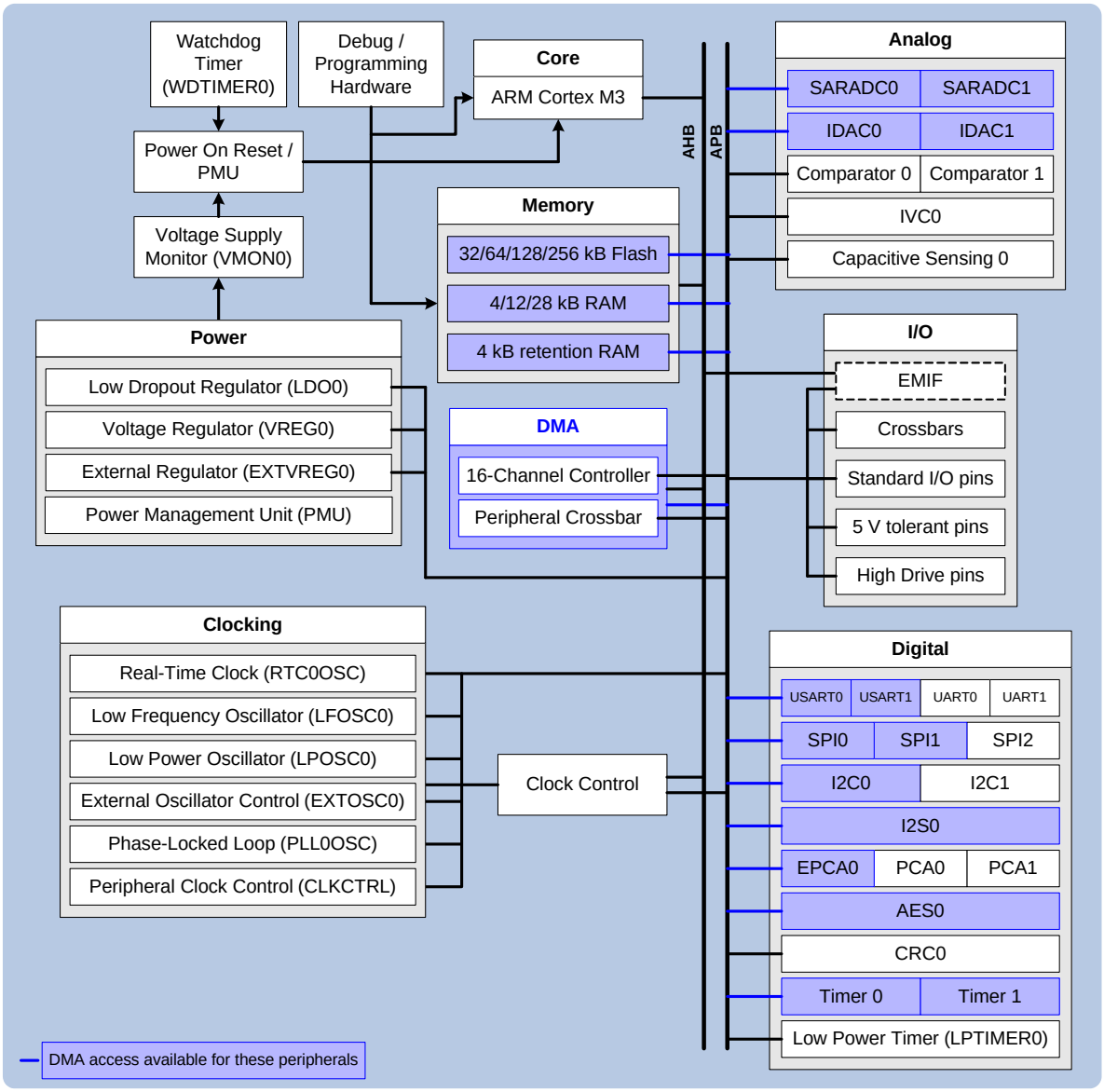


Figure 4.1. Precision32™ SiM3C1xx Family Block Diagram

4.1.5. Device Power Modes

The SiM3C1xx devices feature four low power modes in addition to normal operating mode. Several peripherals provide wake up sources for these low power modes, including the Low-Power Timer (LPT0), RTC0 (alarms and oscillator failure notification), Comparator 0, and PMU Pin Wake.

In addition, all peripherals can have their clocks disabled to reduce power consumption whenever a peripheral is not being used using the clock control (CLKCTRL) registers.

4.1.5.1. Normal Mode (Power Mode 0)

Normal Mode is the default mode of the device. The core and peripherals are fully operational, and instructions are executed from flash memory.

4.1.5.2. Power Mode 1

In Power Mode 1 the core and peripherals are fully operational, with instructions executing from RAM. Compared with Normal Mode, the active power consumption of the device in PM1 is reduced. Additionally, at higher speeds in PM1, the core throughput can also be increased because RAM does not require additional wait states that reduce the instruction fetch speed.

4.1.5.3. Power Mode 2

In Power Mode 2 the core halts and any enabled peripherals continue to run at the selected clock speed. The power consumption in PM2 corresponds to the AHB and APB clocks left enabled, thus the power can be tuned to the optimal level for the needs of the application. To place the device in PM2, the core should execute a wait-for-interrupt (WFI) or wait-for-event (WFE) instruction. If the WFI instruction is called from an interrupt service routine, the interrupt that wakes the device from PM2 must be of a sufficient priority to be recognized by the core. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Syncronization Barrier) operation prior to the WFI to ensure all bus accesses complete. When operating from the LFOSC0 with the DMACTRL0 AHB clock disabled, PM2 can achieve similar power consumption to PM3, but with the ability to wake on APB-clocked interrupts. For example, enabling only the APB clock to the Ports will allow the firmware to wake on a PMATCH0, PBEXT0 or PBEXT1 interrupt with minimal impact on the supply current.

4.1.5.4. Power Mode 3

In Power Mode 3, the AHB and APB clocks are halted. The device may only wake from enabled interrupt sources which do not require the APB clock (RTC0ALRM, RTC0FAIL, LPTIMER0, VDDLOW and VREGLOW). A special fast wake option allows the device to operate at a very low level from the RTC0TCLK or LFOSC0 oscillator while in PM3, but quickly switch to the faster LPOSC0 when the wake event occurs. Because the current consumption of these blocks is minimal, it is recommended to use the fast wake option.

The device will enter PM3 on a WFI or WFE instruction. Because all AHB master clocks are disabled, the LPOSC will automatically halt and go into a low-power suspended state. If the WFI instruction is called from an interrupt service routine, the interrupt that wakes the device from PM3 must be of a sufficient priority to be recognized by the core. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Synchronization Barrier) operation prior to the WFI to ensure all bus access is complete.

4.1.5.5. Power Mode 9

In Power Mode 9, the core and all peripherals are halted, all clocks are stopped, and the pins and peripherals are set to a lower power mode. In addition, standard RAM contents are not preserved, though retention RAM contents are still available after exiting the power mode. This mode provides the lowest power consumption for the device, but requires an appropriate reset to exit. The available reset sources to wake from PM9 are controlled by the Power Management Unit (PMU).

Before entering PM9, the desired reset source(s) should be configured in the PMU. The SLEEPDEEP bit in the ARM System Control Register should be set, and the PMSEL bit in the RSTSRC0_CONFIG register must be set to indicate that PM9 is the desired power mode.

The device will enter PM9 on a WFI or WFE instruction, and remain in PM9 until a reset configured by the PMU occurs. It is recommended to perform both a DSB (Data Synchronization Barrier) and an ISB (Instruction Synchronization Barrier) operation prior to the WFI to ensure all bus access is complete.

4.2. I/O

4.2.1. General Features

The SiM3C1xx ports have the following features:

- Push-pull or open-drain output modes and analog or digital modes.
- Option for high or low output drive strength.
- Port Match allows the device to recognize a change on a port pin value.
- Internal pull-up resistors are enabled or disabled on a port-by-port basis.
- Two external interrupts with up to 16 inputs provide monitoring capability for external signals.
- Internal Pulse Generator Timer (PB2 only) to generate simple square waves.
- A subset of pins can also serve as inputs to the Port Mapped Level Shifters available on the High Drive Pins.

4.2.2. High Drive Pins (PB4)

The High Drive pins have the following additional features:

- Programmable safe state: high, low, or high impedance.
- Programmable drive strength and slew rates.
- Programmable hardware current limiting.
- Powered from a separate source (VIOHD, which can be up to 6 V) from the rest of the device.
- Supports various functions, including GPIO, UART1 pins, EPCA0 pins, or Port Mapped Level Shifting.

4.2.3. 5 V Tolerant Pins (PB3)

The 5 V tolerant pins can be connected to external circuitry operating at voltages above the device supply without needing extra components to shift the voltage level.

4.2.4. Crossbars

The SiM3C1xx devices have two Crossbars with the following features:

- Flexible peripheral assignment to port pins.
- Pins can be individually skipped to move peripherals as needed for design or layout considerations.

The Crossbars have a fixed priority for each I/O function and assign these functions to the port pins. When a digital resource is selected, the least-significant unassigned port pin is assigned to that resource. If a port pin is assigned, the Crossbars skip that pin when assigning the next selected resource. Additionally, the Crossbars will skip port pins whose associated bits in the PBSKIPEN registers are set. This provides some flexibility when designing a system: pins involved with sensitive analog measurements can be moved away from digital I/O and peripherals can be moved around the chip as needed to ease layout constraints.

- Spike suppression up to 2 times the APB period.

4.6.6. I²S (I2S0)

The I²S module receives digital data from an external source over a data line in the standard I²S, left-justified, right-justified, or time domain multiplexing format, de-serializes the data, and generates requests to transfer the data using the DMA. The module also reads stereo audio samples from the DMA, serializes the data, and sends it out of the chip on a data line in the same standard serial format for digital audio. The I²S receive interface consists of 3 signals: SCK (bit clock), WS (word select or frame sync), and SD (data input). The block's transmit interface consists of 3 signals: SCK (bit clock), WS (word select or frame sync) and SD (data output).

The I²S module includes the following features:

- Master or slave capability.
- Flexible 10-bit clock divider with 8-bit fractional clock divider provides support for various common sampling frequencies (16 kHz, 22.05 kHz, 24 kHz, 32 kHz, 44.1 kHz, and 48 kHz) for up to two 32-bit channels.
- Support for DMA data transfers.
- Support for various data formats.
- Time Division Multiplexing

Table 6.2. Pin Definitions and alternate functions for SiM3C1x6 (Continued)

Pin Name	Type	Pin Numbers	Crossbar Capability (see Port Config Section)	Port Match	External Memory Interface (m = muxed mode)	Port-Mapped Level Shifter	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
PB1.8	Standard I/O	30	XBR0	✓	AD14m/ A6			WAKE.2	ADC1.3 CS0.12
PB1.9	Standard I/O	29	XBR0	✓	AD13m/ A5			WAKE.3	ADC1.2 CS0.13
PB1.10	Standard I/O	28	XBR0	✓	AD12m/ A4			DMA0T1 WAKE.4	ADC1.1 CS0.14
PB1.11	Standard I/O	27	XBR0	✓	AD11m/ A3			DMA0T0 WAKE.5	ADC1.0 CS0.15 PMU_Asleep
PB1.12	Standard I/O	26	XBR0	✓	AD10m/ A2			WAKE.6	
PB1.13	Standard I/O	23	XBR0	✓	AD9m/ A1				
PB1.14	Standard I/O	22	XBR0	✓	AD8m/ A0				
PB1.15	Standard I/O	21	XBR0	✓	AD7m/ D7				
PB2.0	Standard I/O	20	XBR1	✓	AD6m/ D6	LSI0	Yes	INT0.0 INT1.0	
PB2.1	Standard I/O	19	XBR1	✓	AD5m/ D5	LSI1	Yes	INT0.1 INT1.1	
PB2.2	Standard I/O	18	XBR1	✓	AD4m/ D4	LSI2	Yes	INT0.2 INT1.2	CMP0N.0 CMP1N.0 RTC0TCLK_OUT
PB2.3	Standard I/O	17	XBR1	✓	AD3m/ D3	LSI3	Yes	INT0.3 INT1.3	CMP0P.0 CMP1P.0
PB3.0	5 V Tolerant I/O	16	XBR1	✓	AD2m/ D2				CMP0P.1 CMP1P.1
PB3.1	5 V Tolerant I/O	15	XBR1	✓	AD1m/ D1				CMP0N.1 CMP1N.1

Table 6.3. Pin Definitions and Alternate Functions for SiM3C1x4

Pin Name	Type	Pin Numbers	Crossbar Capability (see Port Config Section)	Port Match	Output Toggle Logic	External Trigger Inputs	Analog or Additional Functions
VSS	Ground	14					
VDD	Power (Core)	35					
VIO	Power (I/O)	13					
VREGIN	Power (Regulator)	36					
VSSHD	Ground (High Drive)	2					
VIOHD	Power (High Drive)	3					
$\overline{\text{RESET}}$	Active-low Reset	40					
SWCLK	Serial Wire	24					
SWDIO	Serial Wire	23					
PB0.0	Standard I/O	34	XBR0	✓			ADC0.8 CS0.7 RTC1
PB0.1	Standard I/O	33	XBR0	✓			RTC2
PB0.2	Standard I/O	32	XBR0	✓			ADC0.9 CS0.0 VREFGND
PB0.3	Standard I/O	31	XBR0	✓			ADC0.10 CS0.1 VREF
PB0.4	Standard I/O	30	XBR0	✓			ADC1.6 CS0.2 IDAC0
PB0.5	Standard I/O	29					IDAC1
PB0.6	Standard I/O	28	XBR0	✓			ADC0.0 CS0.3 XTAL1
PB0.7	Standard I/O	27	XBR0	✓			ADC0.1 CS0.4 XTAL2

6.4. LGA-92 Package Specifications

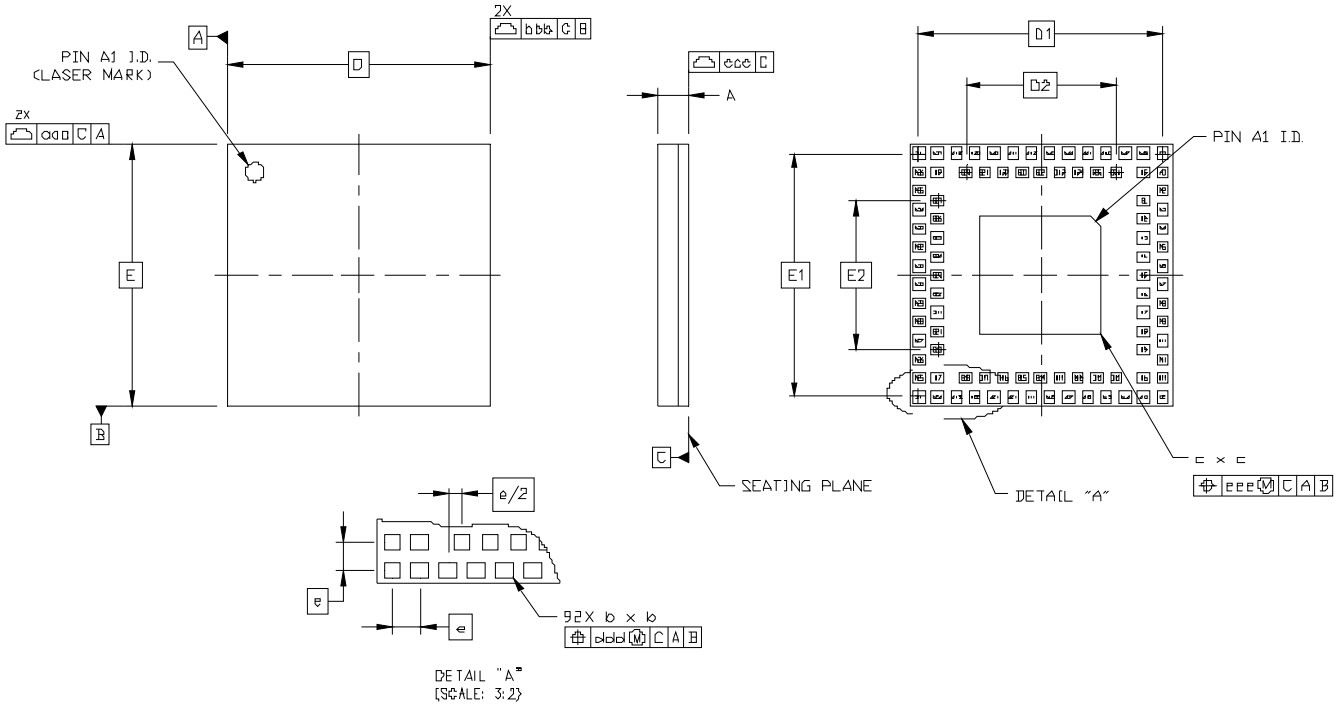


Figure 6.6. LGA-92 Package Drawing

Table 6.4. LGA-92 Package Dimensions

Dimension	Min	Nominal	Max
A	0.74	0.84	0.94
b	0.25	0.30	0.35
c	3.15	3.20	3.25
D		7.00 BSC	
D1		6.50 BSC	
D2		4.00 BSC	
e		0.50 BSC	
E		7.00 BSC	
E1		6.50 BSC	
E2		4.00 BSC	
aaa	—	—	0.10
bbb	—	—	0.10
ccc	—	—	0.08
ddd	—	—	0.10
eee	—	—	0.10

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6.5. TQFP-80 Package Specifications

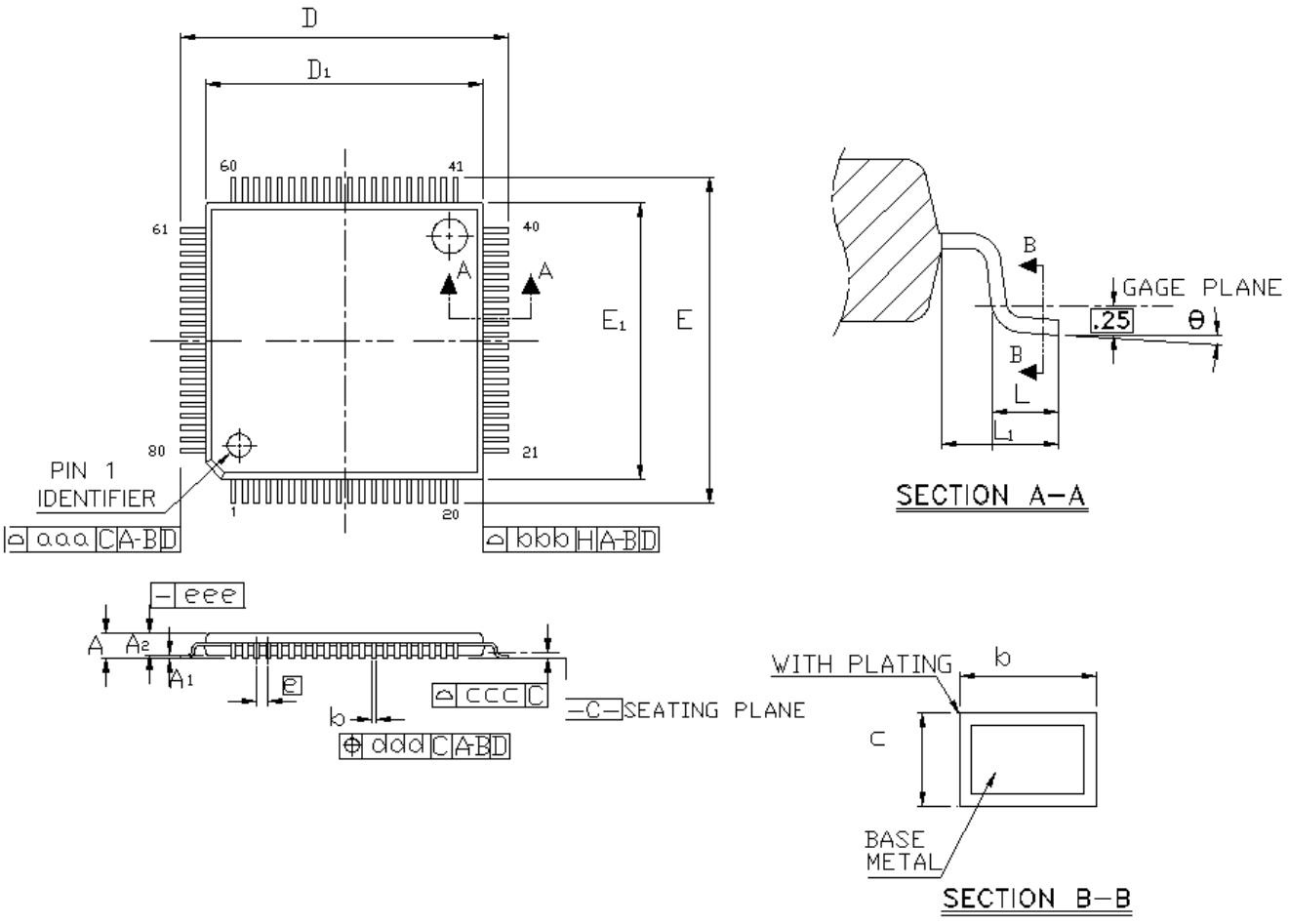


Figure 6.8. TQFP-80 Package Drawing

Table 6.6. TQFP-80 Package Dimensions

Dimension	Min	Nominal	Max
A	—	—	1.20
A1	0.05	—	0.15
A2	0.95	1.00	1.05
b	0.17	0.20	0.27
c	0.09	—	0.20
D	14.00 BSC		
D1	12.00 BSC		
e	0.50 BSC		
E	14.00 BSC		
E1	12.00 BSC		

Table 6.6. TQFP-80 Package Dimensions (Continued)

Dimension	Min	Nominal	Max
L	0.45	0.60	0.75
L1		1.00 Ref	
Θ	0°	3.5°	7°
aaa		0.20	
bbb		0.20	
ccc		0.08	
ddd		0.08	
eee		0.05	

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This package outline conforms to JEDEC MS-026, variant ADD.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

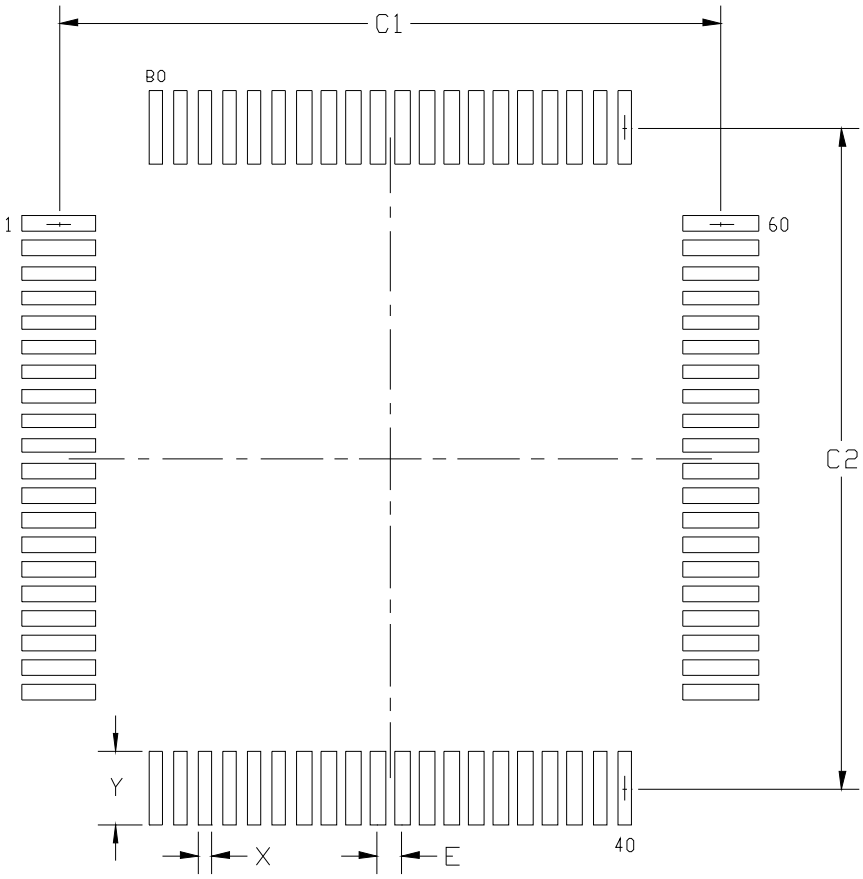


Figure 6.9. TQFP-80 Landing Diagram

Table 6.7. TQFP-80 Landing Diagram Dimensions

Dimension	Min	Max
C1	13.30	13.40
C2	13.30	13.40
E	0.50 BSC	
X	0.20	0.30
Y	1.40	1.50

Notes:
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This land pattern design is based on the IPC-7351 guidelines.

6.6. QFN-64 Package Specifications

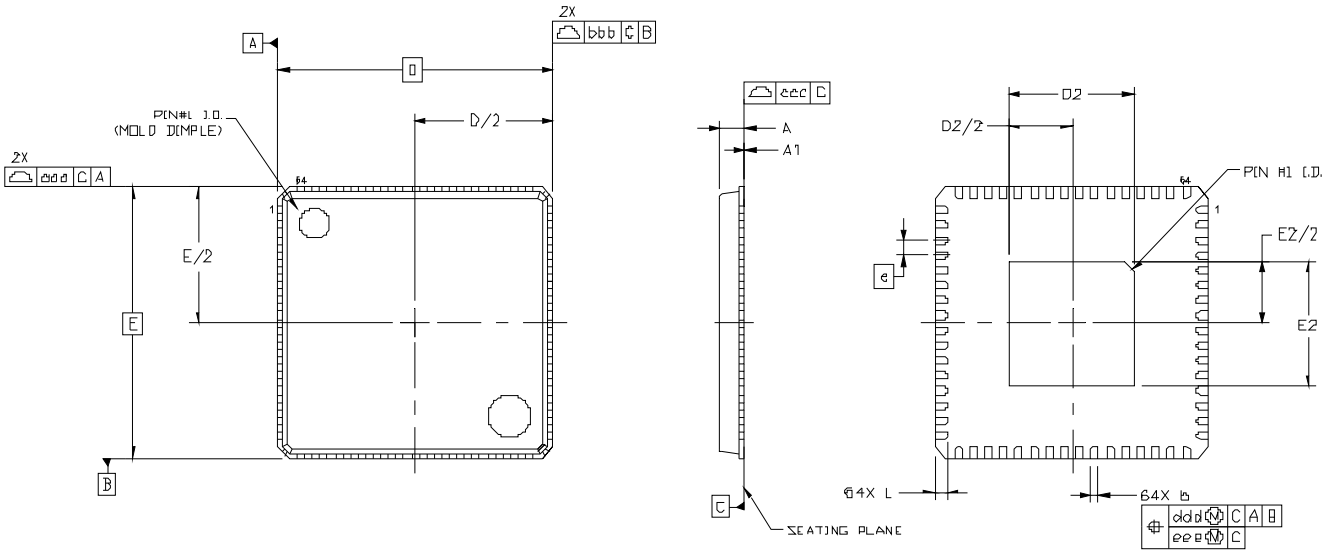


Figure 6.10. QFN-64 Package Drawing

Table 6.8. QFN-64 Package Dimensions

Dimension	Min	Nominal	Max
A	0.80	0.85	0.90
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D		9.00 BSC	
D2	3.95	4.10	4.25
e		0.50 BSC	
E		9.00 BSC	
E2	3.95	4.10	4.25
L	0.30	0.40	0.50
aaa		0.10	
bbb		0.10	
ccc		0.08	
ddd		0.10	
eee		0.05	

Notes:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This package outline conforms to JEDEC MO-220.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

6.6.1. QFN-64 Solder Mask Design

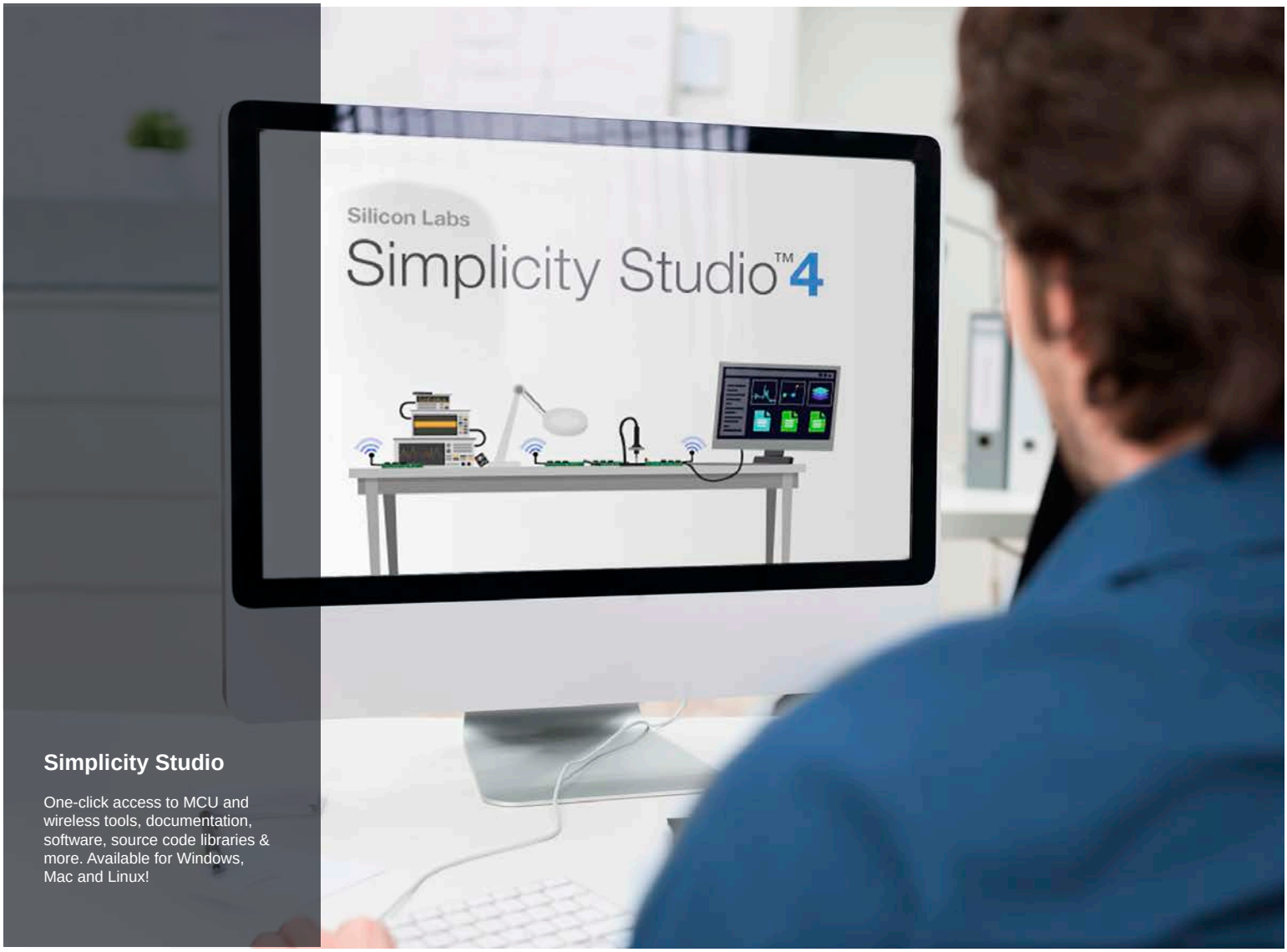
All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.

6.6.2. QFN-64 Stencil Design

1. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
2. The stencil thickness should be 0.125 mm (5 mils).
3. The ratio of stencil aperture to land pad size should be 1:1 for all pads.
4. A 3x3 array of 1.0 mm square openings on a 1.5 mm pitch should be used for the center ground pad.

6.6.3. QFN-64 Card Assembly

1. A No-Clean, Type-3 solder paste is recommended.
2. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.



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